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Artificial Intelligence and Machine Learning in Cybersecurity Frontiers: Insights from Industry 4.0 and Innovations for Industry 5.0

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Message from the Guest Editors

Dear Colleagues,

In this Special Issue, titled "Machine Learning Security in Industry 4.0: Opportunities, Challenges, and Innovations," we invite scholars and professionals from around the globe to share their cutting-edge research, innovative strategies, and insightful experiences. We aim to create a knowledge hub that sparks exciting discussions, advances scientific understanding, and catalyzes transformative solutions for securing our digital future.

The Special Issue will spotlight a broad spectrum of research areas, including:

- Innovative Intrusion Detection Models
- Revolutionizing Risk Assessment
- Automated Incident Response and Playbook Design
- Next-Level Threat Intelligence Sharing
- Securing ML Models Against Cyber Attacks











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Message from the Editor-in-Chief

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